

Cambridge University Press & Assessment

978-1-605-11222-0 — Amorphous and Polycrystalline Thin-Film Silicon Science and Technology — 2010

Edited by Qi Wang, Baojie Yan, Andrew Flewitt, Chuang-Chuang Tsai, Seiichiro Higashi

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## CAMBRIDGE UNIVERSITY PRESS

University Printing House, Cambridge CB2 8BS, United Kingdom

One Liberty Plaza, 20th Floor, New York, NY 10006, USA

477 Williamstown Road, Port Melbourne, VIC 3207, Australia

314-321, 3rd Floor, Plot 3, Splendor Forum, Jasola District Centre, New Delhi - 110025, India

103 Penang Road, #05-06/07, Visioncrest Commercial, Singapore 238467

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[www.cambridge.org](http://www.cambridge.org)

Information on this title: [www.cambridge.org/9781605112220](http://www.cambridge.org/9781605112220)

Materials Research Society

506 Keystone Drive, Warrendale, PA 15086

<http://www.mrs.org>

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First published 2010

First paperback edition 2012

Single article reprints from this publication are available through

University Microfilms Inc., 300 North Zeeb Road, Ann Arbor, MI 48106

CODEN: MRSPDH

*A catalogue record for this publication is available from the British Library*

ISBN 978-1-605-11222-0 Hardback

ISBN 978-1-107-40800-5 Paperback

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